



Space-Charge and Circuit-Induced Distortion of Short-Pulse Beams in a Vacuum Diode

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Summary

- Short-pulse electron beam dynamics in vacuum diodes are strongly shaped by space-charge effects and the external circuit.
- Multiple-sheet model and WarpX PIC simulations self-consistently resolve the electric fields, charge transport, and circuit response.

Multiple-Sheet Model

A **grid-less solver** for one-dimensional (1D) diode with gap distance d and source voltage V_0 , with a series resistor R , and with electron beam modeled as sheets inside the gap.

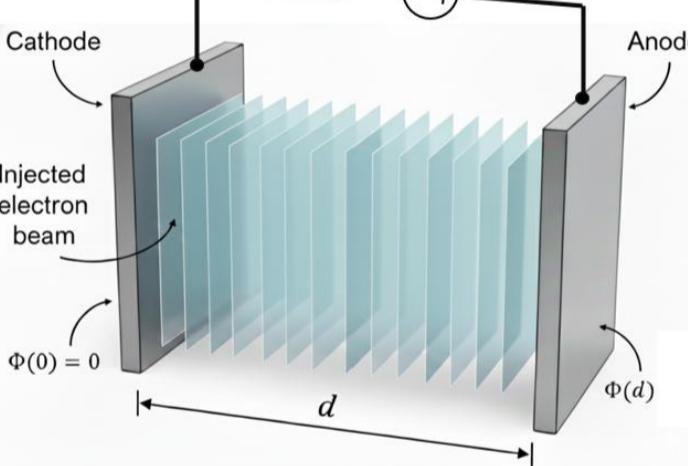


Figure 1: Sheet positions inside the diode gap

- The Electric field on sheet j of density ρ_j at position z_j with velocity v_j is

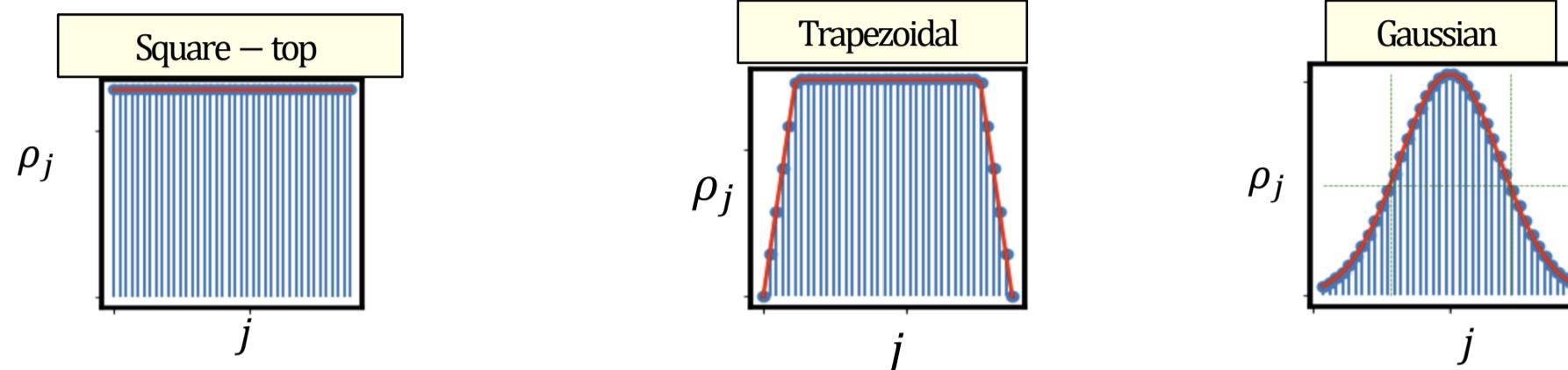
$$E_j = -\frac{V_g}{d} - \frac{1}{\epsilon_0} \left(\sum_{i=1}^M \rho_i \frac{z_i}{d} - \sum_{i=1}^{j-1} \rho_i + \frac{1}{2} \rho_j \right) \quad (1)$$

where $V_g = V_0 - RI(t)$ and $I(t)$ is the sum of the conduction and displacement current across the gap

$$I(t) = \frac{A}{d} \sum_{i=1}^M \rho_i v_i - \frac{\epsilon_0 A}{d} R \frac{dI(t)}{dt} \quad (2)$$

- These equations are coupled to the Newton's equations of motion.

Short-Pulse Profiles



- The normalized charge density: $f = \rho / (-\epsilon_0 V_0 / d)$
- The normalized pulse duration: $k = \tau_p / (3d \sqrt{2eV_0/m_e})$

with transit time: $T_{CL} = \tau_p / (3d \sqrt{2eV_0/m_e})$

Electron trajectories using the Multiple-sheet solver

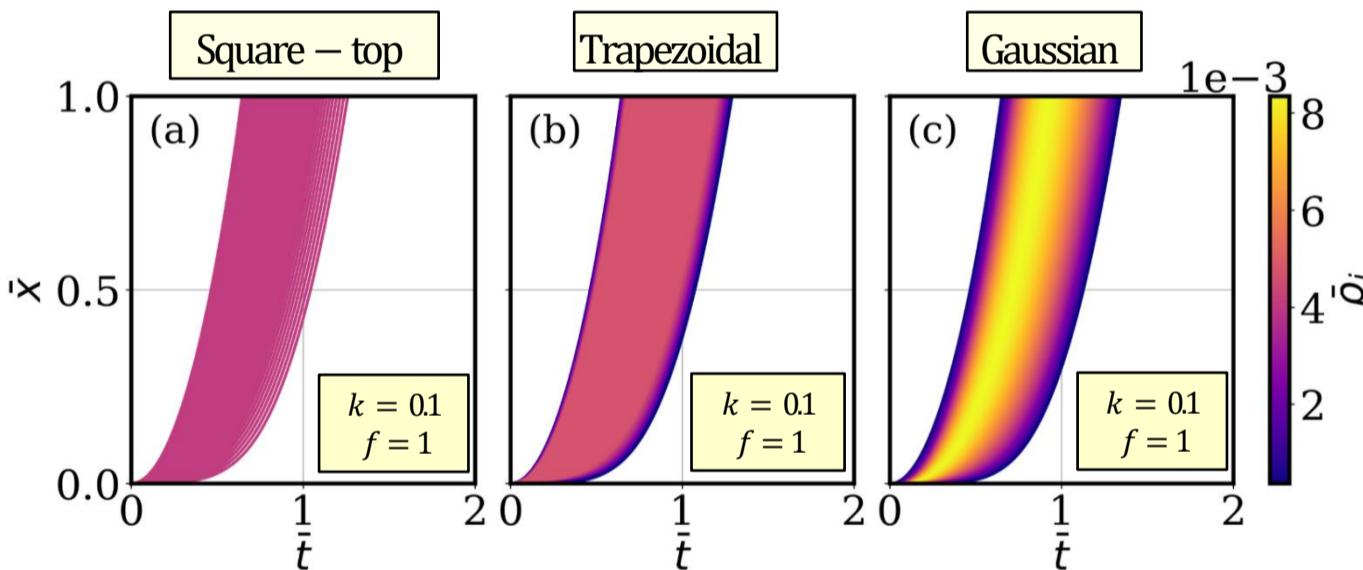


Figure 2: Electron sheet trajectories in vacuum with $R = 0 \Omega$ [1]

WarpX Simulation with circuit coupling

We use the discretization of [Eq. \(2\)](#), presented in [Table 1](#), to implement the circuit coupling in WarpX.

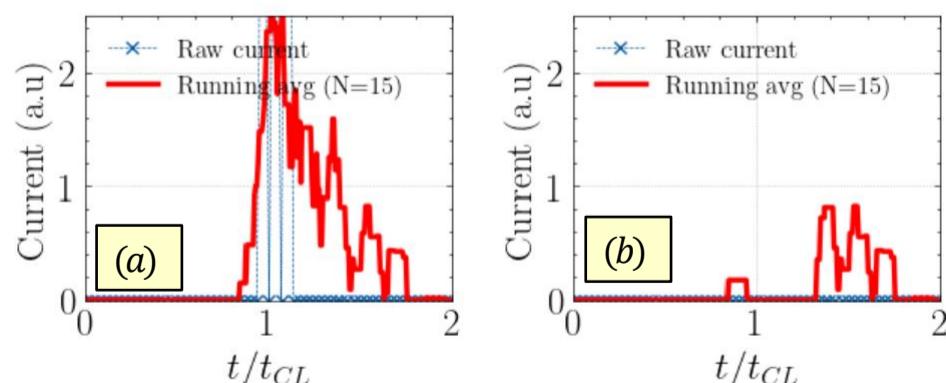


Figure 3: Diode current for (a) $R = 0 \Omega$, and (b) $R = 10^3 \Omega$ for a Square-top pulse, with $f = 0.95$, $k = 0.1$, $d = 2.8 \text{ mm}$ and $V_0 = 50 \text{ V}$

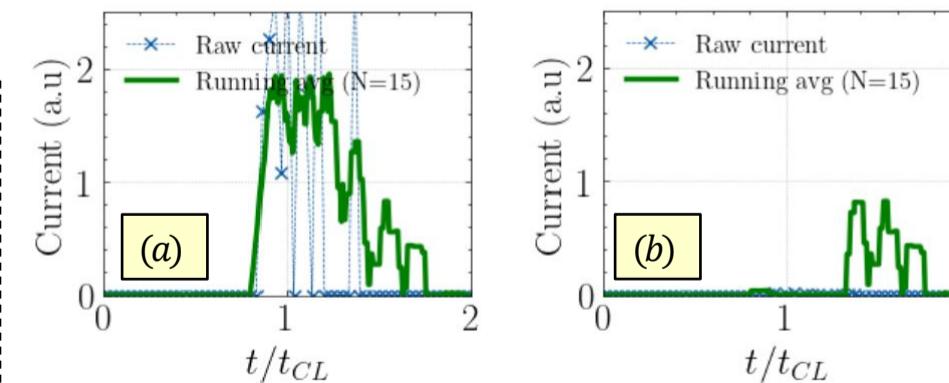


Figure 4: Diode current for (a) $R = 0 \Omega$, and (b) $R = 10^3 \Omega$ for a Gaussian pulse, with $f = 0.95$, $k = 0.1$, $d = 2.8 \text{ mm}$ and $V_0 = 50 \text{ V}$

Table 1: Discretization with a backward-Euler

$$I^{n+1} = I_{\text{cond}}^{n+1} - \beta \frac{I^{n+1} - I^n}{\Delta t} \quad (A)$$

$$I^{n+1} \left(1 + \frac{\beta}{\Delta t} \right) = I_{\text{cond}}^{n+1} + \frac{\beta}{\Delta t} I^n \quad (B)$$

$$I^{n+1} = \frac{I_{\text{cond}}^{n+1} + \beta / \Delta t I^n}{(1 + \beta / \Delta t)} \quad (C)$$

Future Work

- 1 Systematic parametric studies for vacuum diodes with series resistor.
- 2 Extend the model to plasma-filled gaps by incorporating ionization, charge exchange, etc.
- 3 Benchmark the plasma-gap formulation experiments data, and relevant scaling laws, on current, voltage with respect to gas pressure and diode parameters.

References & Acknowledgement

- 1 Y. Heri and P. Zhang, IEEE Trans. Electron Devices 72, 2591 (2025).
- 2 C. Birdsall and W. Bridges (1966). Electron dynamics of diode regions. New York: Academic Press
- 3 P. Zhang, W. S. Koh, L. K. Ang, S. H. Chen; Phys. Plasmas 1 June 2008; 15 (6): 063105.

Acknowledgement: This work is supported in part by the Office of Naval Research (ONR) Young Investigator Program (YIP) under Grant N00014-20-1-2681, in part by the Air Force Office of Scientific Research (AFOSR) under Grant FA9550-20-1-0409 and Grant FA9550-22-1-0523, and in part by the National Science Foundation (NSF) under Grant 2516752.